

*मसौदा भारतीय मानक*

**पहचान पत्र – संपर्क रहित एकीकृत सर्किट कार्ड– प्रॉक्सिमिटी कार्ड –  
एकल पीसीडी क्षेत्र में एकाधिक पीआईसीसी**

*Draft Indian Standard for comment*

**Identification cards — Contactless integrated circuit cards —  
Proximity cards — Multiple PICCs in a single PCD field**

ICS 35.240.15

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**BUREAU OF INDIAN STANDARDS**  
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## NATIONAL FOREWORD

This draft Indian Standard which is identical with ISO/IEC TR 18268:2013 ‘Identification cards — Contactless integrated circuit cards — Proximity cards — Multiple PICCs in a single PCD field’ issued by the International Organization for Standardization (ISO) and International Electrotechnical Commission (IEC) jointly, may be adopted by the Bureau of Indian Standards on the recommendation of the Identification and Data capture techniques, Cards and Security Devices Sectional Committee, and approval of the Electronics and Information Technology Division Council.

The text of ISO/IEC Standard has been approved as suitable for publication as an Indian Standard without deviations. Certain conventions are, however, not identical to those used in Indian Standards. Attention is particularly drawn to the following:

- 1) Wherever the words ‘International Standard’ appears referring to this standard, they should be read as ‘Indian Standard’.
- 2) Comma (,) has been used as a decimal marker while in Indian Standards, the current practice is to use a point (.) as the decimal marker.

For the purpose of deciding whether a particular requirement of this standard is complied with, the final value, observed or calculated, expressing the result of a test or analysis, shall be rounded off in accordance with IS 2:1960 ‘Rules for rounding off numerical values (revised)’. The number of significant places retained in the rounded off value should be the same as that of the specified value in this standard.

### **Scope of ISO/IEC TR 18268:2013 is as follows:**

This Technical Report presents a collation of industry experience of technical issues resulting from the presence of multiple PICCs in the field of a PCD. It describes how resonance frequencies may shift, how individual PICCs may see a reduced field strength, how multiple PICCs load the PCD, how they may change the local modulation signal and how PICCs should manage their identities to aid support of simultaneous usage. Scenarios for electronic passports with multiple visas and wallets containing multi-industry cards are explored.

Note: Technical content of this document has not been enclosed as these are identical with the corresponding IEC Standard, for details please refer ISO/IEC TR 18268:2013 or kindly contact.

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